

10/088404
1010 HALL PATENT 18 MAR 2002
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Beil et al.

Examiner: #3

Serial No.: Not yet assigned

Group Art Unit:

Filed: Herewith

Docket: 298-157

For: DEVICE AND METHOD FOR
HIGH-SENSITIVITY RESOLUTION DETECTION

Dated: March 18, 2002

Assistant Commissioner for Patents
Washington, D.C. 20231

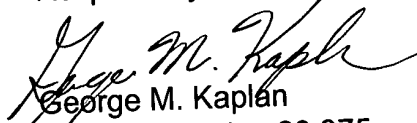
LETTER

Sir:

Please make of record the art (copies enclosed) listed upon accompanying Form PTO-1449 and which was cited in the Search Report (copy enclosed) of the priority PCT application.

Streibl et al. were published after the priority date of the above-identified application.

Respectfully submitted,


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CERTIFICATION UNDER 37 C.F.R. § 1.10

I hereby certify that this correspondence and the documents referred to as enclosed are being deposited with the United States Postal Service on date below in an envelope as "Express Mail Post Office to Addressee" Mail Label Number **EL918809416US** addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231.

Dated: March 18, 2002


George M. Kaplan

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO.

298-157

SERIAL NO.

APPLICANT

HARRIS ET AL.

FILING DATE

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GROUP

Art Unit: n/a

U.S. PATENT DOCUMENT

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5 8 5 0 1 1 8	12/98	TODA			
	5 8 3 1 4 9 2	11/98	SOLIE			
	4 6 0 0 9 0 5	07/86	FREDRICKSEN			
	5 8 1 8 3 1 0	10/98	SOLIE			

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	
1 9 7 0 6 4 86	08/98	FED. REP. GERMANY			

Streibl, M. et al. "SAW Tomography-Spatially Resolved Charge Detection by SAW in Semiconductor Structures

for Imaging Applications", 1999 IEEE Ultrasonics Symposium Proceedings. International Symposium (Cat. No. 99CH 37027),

1999 IEEE Ultrasonics Symposium, Proceedings. International Symposium. Caesars Tahoe, NV, U.S.A. 17-20 Oct. 1999, Pages

11-14, Vol. 1, XP002156577, 1999, Piscataway, NJ, U.S.A., IEEE, U.S.A., ISBN: 0-7803-5722-1

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(Form PTO-1449 [6-4])